

















Fully automated, mixed-signal electro-optical test systems for optoelectronics and singulated photonic devices. Featuring DC, RF and optical measurements in a production-optimized modular layout, and targeted at R&D, volume manufacturing, and anything in between.









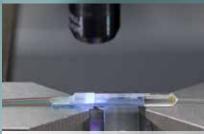
Fully automated single device electro-optical test

ficonTEC's Testune production systems are fully automated solutions for electro-optical testing of optoelectronic devices and of singulated PICs (passive/active). Other complex tasks include LIV, spectral and near/far-field beam characterization of single laser chips (incl. VCSELs), unmounted laser diode bars and chip-on-submount (CoS) sources. Lastly, Testune systems can be routinely equipped to also perform detailed optical facet inspection using Deep Learning for defect recognition.

Stand-alone systems are designed to provide as much multi-functional test-&-qualify capability as possible and are best suited to complex testing requirements requiring multiple capabilities within a single machine. This makes the stand-alone systems ideal for test development and for batch processing requirements.

ficonTEC's next-generation in-line system architecture is designed to be production-line-capable from the ground up. By utilizing state-of-the-art component handling and feed in/out options, Testune and Assemblyune systems can be combined in a task-optimized production line configuration to provide volume-capable manufacturing.

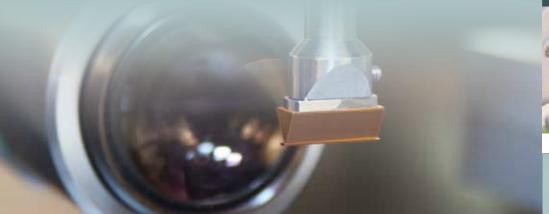




Dual fiber array alignment (active test)



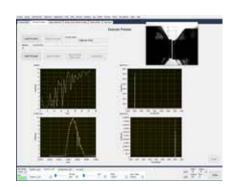
LIV characterization



Software Control

PROCESS CONTROL MASTER (PCM) is ficonTEC's unified process-oriented control interface that ships with all turn-key stand-alone systems and multiple machine configurations. PCM features an intuitive UI that includes all machine vision, high-resolution positioning and system management software routines required to reliably and repeatably drive test process hardware.

PCM is fully enabled for automated mixed-signal electro-optical test and characterization tasks, as well as providing machine vision support for I/O probe-to-port alignment. An up-to-date feature set includes Al-based Deep Learning defect recognition capability, ML-oriented monitoring of production performance data, and the possibility to direct call functions in Python files.



Spectral and beam characterization functions displayed in real time











High-precision motion referencing and alignment

- Die-level handling, testing and sorting as required
- Fiber alignment to I/O ports (arrays) in max. 4s
- Low-loss I/O port coupling with < 0.4 dB repeatability

Modular & (re-)configurable

- State-of-the-art die and carrier handling options
- FAB & HVM-ready scalable and parallelizable

General tasks & applications

Key features

- Rapid R&D, in-line & end-of-line device testing
- Optical facet inspection with AI defect recognition
- Test-&-qualify of chips, single emitters, laser bars, PICs, silicon photonics, hybrid devices
- Applications in telecom/datacom/5G, sensors and lidar, transport & IoT, 3D scanning & healthcare

TESTLINE is PXI-capable

to match individual requirements. Non-LabVIEW and







MANUFACTURING MADE LIGHT

Solutions for integrated photonics. Built to scale.

ficonTEC is the global market leader for automated assembly and test systems for modern optoelectronics and integrated photonic devices. An unequalled breadth in process capability has been developed in serving the needs of a broad range of applications, including telecom/datacom and 5G, sensors and lidar, IoT and mobility, high-power diode laser assembly, and many more.

A unique and modular approach to production equipment design means that each system delivered is the automated and optimized embodiment of a customer-defined process.

Contact us

ficonTEC Service GmbH Achim, Germany

T +49 4202 51160-0 info@ficontec.com

For ficonTEC subsidiaries and distributors around the globe:





Core system specifications	T800	T1200	T1600	T2000
Motion system	single optical probing with 6-axis high-precision alignment* electrical probing with 3-axis alignment	multiple optical probing with 6-axis high-precision alignment* electrical probing with 3-axis alignment		
Device handling	pick-&-place Gel-Pak, Waffle Pa			
Temperature control	temperature-controlled chuck, +15 to +80 (+/- 0.1) °C			
Handling options	manual loading and/or single conveyor	automated loading with single or dual conveyor		
Machine vision	system referencing and observation camera options device and I/O port referencing			
Software features	flexible and powerful process programming extended operator-less control Windows 10 PC			
Minimum connections	120 VAC (or country specific) air/vacuum 100 Mbit/s network			
Cleanroom compliance	ISO 6**			
Physical features	rugged steel base production cell			
Dimensions (w x b x h, mm)	800 x 1200 x 1600/2000	1200 x 1200 x 2000	1600 x 1200 x 2000	1800 x 1200 x 2000
Weight (typ., kg)	1300	1800	2300	2500
* alternative multi-axis configurations optional ** others available on request				

TESTLINE systems are suitable for single, batch and volume testing of optoelectronics and singulated PIC devices. Multiple systems can be remotely controlled and operated in parallel and in sync. Custom systems, special purpose cells and robotic systems can be flexibly incorporated to suit customer requirements. Some TESTLINE functionality is available in ASSEMBLYLINE systems.